

L Number	Hits	Search Text	DB	Time stamp
1	4957	"5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex\$3) near (relay relays relayed relaying switch switching switched switches)))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:45
2	1284	("5" and (((relay relays relayed relaying switch switching switched switches) with circuit) and ((fanout "fan out" serial-to-parallel multiplex\$3) near (relay relays relayed relaying switch switching switched switches))) ) and (latch and clock)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 14:47
	1403	((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
	68	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 12:59
	310	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 11:56
	60	((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flip flop register))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:21
	885	714/704.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:00
	0	(((((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)) and ((clock clocks) with (latch "shift register" flip-flop flip flop register))) and (fan-out "fan out" fanout)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 12:06
	1408020	DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/09 16:26
	311	((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ti. ((DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))).ab.) and (relay relays switch switches)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:07

	16361	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:13
	25770	(DUT "device under test" device-under-test CUT "circuit under test" circuit-under-test SUT "system under test" system-under-test (circuit near test\$3)) and (test near (data signal input pattern source information))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/06/10 13:54